



## Polarization imaging: Current Status and Prospects

Guest Editor:

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### Message from the Guest Editor

Reflected or scattered optical polarization information from the surface of materials can reveal their physical and chemical characteristics. Therefore, optical polarization imaging has the advantageous ability to improve the contrast between the target and the background, and thus increase the detection distance in the turbid medium. As such, it is providing new possibilities for industrial testing, biomedical diagnosis and object identification.

We welcome contributions from experts and scholars from both academia and industry, which focus on specific research topics that include, but are not limited to, the following:

- fundamental theoretical research on polarized light
- polarization imaging methods and systems
- polarized reflection/radiation characteristics
- polarized light transmission characteristics
- the polarization image enhancement algorithm
- polarization imaging applications
- combining polarization information with artificial intelligence and machine learning techniques





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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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